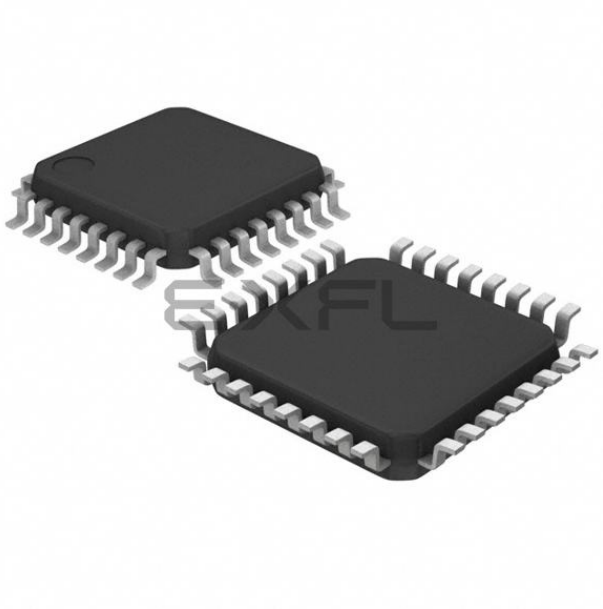

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Discontinued at Digi-Key
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	25MHz
Connectivity	EBI/EMI, I²C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	24
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4.25K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 23x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	32-QFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8sb20f32g-a-qfp32r

1. Feature List

The EFM8SB2 highlighted features are listed below.

- Core:
  - Pipelined CIP-51 Core
  - Fully compatible with standard 8051 instruction set
  - 70% of instructions execute in 1-2 clock cycles
  - 25 MHz maximum operating frequency
- Memory:
  - Up to 64 kB flash memory, in-system re-programmable from firmware.
  - Up to 4352 bytes RAM (including 256 bytes standard 8051 RAM and 4096 bytes on-chip XRAM)
- Power:
  - Internal LDO regulator for CPU core voltage
  - Power-on reset circuit and brownout detectors
- I/O: Up to 24 total multifunction I/O pins:
  - Flexible peripheral crossbar for peripheral routing
  - 5 mA source, 12.5 mA sink allows direct drive of LEDs
- Clock Sources:
  - Internal 20 MHz low power oscillator with ±10% accuracy
  - Internal 24.5 MHz precision oscillator with ±2% accuracy
  - External RTC 32 kHz crystal
  - External crystal, RC, C, and CMOS clock options
- Timers/Counters and PWM:
  - 32-bit Real Time Clock (RTC)
  - 6-channel programmable counter array (PCA) supporting PWM, capture/compare, and frequency output modes with watchdog timer function
  - 4 x 16-bit general-purpose timers
- Communications and Digital Peripherals:
  - UART
  - 2 x SPI™ Master / Slave
  - SMBus™/I2C™ Master / Slave
  - External Memory Interface (EMIF)
  - 16-bit/32-bit CRC unit, supporting automatic CRC of flash at 1024-byte boundaries
- Analog:
  - Programmable current reference (IREF0)
  - 10-Bit Analog-to-Digital Converter (ADC0)
  - 2 x Low-current analog comparators
- On-Chip, Non-Intrusive Debugging
  - Full memory and register inspection
  - Four hardware breakpoints, single-stepping
- Pre-loaded UART bootloader
- Temperature range -40 to 85 ºC
- Single power supply 1.8 to 3.6 V
- QFP32, QFN32, and QFN24 packages

With on-chip power-on reset, voltage supply monitor, watchdog timer, and clock oscillator, the EFM8SB2 devices are truly standalone system-on-a-chip solutions. The flash memory is reprogrammable in-circuit, providing non-volatile data storage and allowing field upgrades of the firmware. The on-chip debugging interface (C2) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging. Each device is specified for 1.8 to 3.6 V operation and is available in 24-pin QFN, 32-pin QFN, or 32-pin QFP packages. All package options are lead-free and RoHS compliant.

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC Channels	Comparator Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8SB20F16G-A-QFN24	16	4352	16	15	8	Yes	-40 to +85 C	QFN24

10-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 10- and 8-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 22 external inputs.
- Single-ended 10-bit mode.
- Supports an output update rate of 300 ksps samples per second.
- Operation in low power modes at lower conversion speeds.
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer sources.
- Output data window comparator allows automatic range checking.
- Support for burst mode, which produces one set of accumulated data per conversion-start trigger with programmable power-on settling and tracking time.
- Conversion complete and window compare interrupts supported.
- Flexible output data formatting.
- Includes an internal 1.65 V fast-settling reference and support for external reference.
- Integrated temperature sensor.

Low Current Comparators (CMP0, CMP1)

Analog comparators are used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator module includes the following features:

- Up to 12 external positive inputs.
- Up to 11 external negative inputs.
- Additional input options:
  - Capacitive Sense Comparator output.
  - VDD.
  - VDD divided by 2.
  - Internal connection to LDO output.
  - Direct connection to GND.
- Synchronous and asynchronous outputs can be routed to pins via crossbar.
- Programmable hysteresis between 0 and +/-20 mV.
- Programmable response time.
- Interrupts generated on rising, falling, or both edges.

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Sleep Mode Supply Current (RTC off)	I_{DD}	1.8 V, T = 25 °C	—	0.05	—	µA
		3.6 V, T = 25 °C	—	0.12	—	µA
		1.8 V, T = 85 °C	—	0.75	—	µA
		3.6 V, T = 85 °C	—	1.20	—	µA
V_{DD} Monitor Supply Current	I_{VMON}		—	7	—	µA
Oscillator Supply Current	I_{HFOSC0}	25 °C	—	300	—	µA
ADC0 Always-on Power Supply Current[7]	I_{ADC}	300 ksps V_{DD} = 3.0 V	—	800	—	µA
		Tracking V_{DD} = 3.0 V	—	680	—	µA
Comparator 0 (CMP0) Supply Current	I_{CMP}	CPMD = 11	—	0.4	—	µA
		CPMD = 10	—	2.6	—	µA
		CPMD = 01	—	8.8	—	µA
		CPMD = 00	—	23	—	µA
Internal Fast-settling 1.65V ADC0 Reference, Always-on[8]	I_{VREFFS}		—	200	—	µA
On-chip Precision Reference	I_{VREFP}		—	15	—	µA
Temp sensor Supply Current	I_{TSENSE}		—	35	—	µA
Programmable Current Reference (IREF0) Supply Current[9]	I_{IREF}	Current Source, Either Power Mode, Any Output Code	—	10	—	µA
		Low Power Mode, Current Sink IREF0DAT = 000001	—	1	—	µA
		Low Power Mode, Current Sink IREF0DAT = 111111	—	11	—	µA
		High Current Mode, Current Sink IREF0DAT = 000001	—	12	—	µA
		High Current Mode, Current Sink IREF0DAT = 111111	—	81	—	µA

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Endurance (Write/Erase Cycles)	N_{WE}		1 k	30 k	—	Cycles

Note:
1. Does not include sequencing time before and after the write/erase operation, which may be multiple SYSCLK cycles.
2. Data Retention Information is published in the Quarterly Quality and Reliability Report.

Table 4.5. Power Management Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Idle Mode Wake-up Time	t_{IDLEWK}		2	—	3	SYSCLKs
Suspend Mode Wake-up Time	$t_{SUS-PENDWK}$	CLKDIV = 0x00 Precision Osc.	—	400	—	ns
		CLKDIV = 0x00 Low Power Osc.	—	1.3	—	µs
Sleep Mode Wake-up Time	$t_{SLEEPWK}$		—	2	—	µs

Table 4.6. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
High Frequency Oscillator 0 (24.5 MHz)						
Oscillator Frequency	f_{HFOSC0}	Full Temperature and Supply Range	24	24.5	25	MHz
Low Power Oscillator (20 MHz)						
Oscillator Frequency	f_{LPOSC}	Full Temperature and Supply Range	18	20	22	MHz
RTC in Self-Oscillate Mode						
Oscillator Frequency	f_{LFOSC}	Bias Off	—	12 ± 5	—	kHz
		Bias On	—	25 ± 10	—	kHz

Table 4.7. Crystal Oscillator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Crystal Frequency	f_{XTAL}		0.02	-	25	MHz

Table 4.8. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	25	MHz
External Input CMOS Clock High Time	t_{CMOSH}		18	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		18	—	—	ns

Table 4.9. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}			10		Bits
Throughput Rate	f_S		—	—	300	ksps
Tracking Time	t_{TRK}		1.5	—	—	µs
Power-On Time	t_{PWR}		1.5	—	—	µs
SAR Clock Frequency	f_{SAR}	High Speed Mode,	—	—	8.33	MHz
Conversion Time	T_{CNV}		13	—	—	Clocks
Sample/Hold Capacitor	C_{SAR}	Gain = 1	—	30	—	pF
		Gain = 0.5	—	28	—	pF
Input Pin Capacitance	C_{IN}		—	20	—	pF
Input Mux Impedance	R_{MUX}		—	5	—	kΩ
Voltage Reference Range	V_{REF}		1	—	V_{DD}	V
Input Voltage Range[1]	V_{IN}	Gain = 1	0	—	V_{REF}	V
		Gain = 0.5	0	—	2 x V_{REF}	V
Power Supply Rejection Ratio	$PSRR_{ADC}$	Internal High Speed VREF	—	67	—	dB
		External VREF	—	74	—	dB
DC Performance						
Integral Nonlinearity	INL		—	±0.5	±1	LSB
Differential Nonlinearity (Guaranteed Monotonic)	DNL		—	±0.5	±1	LSB
Offset Error	E_{OFF}	VREF = 1.65 V	–2	0	2	LSB
Offset Temperature Coefficient	TC_{OFF}		—	0.004	—	LSB/°C
Slope Error	E_M		—	±0.06	±0.24	%
Dynamic Performance 10 kHz Sine Wave Input 1dB below full scale, Max throughput						
Signal-to-Noise	SNR		54	58	—	dB
Signal-to-Noise Plus Distortion	SNDR		54	58	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD		—	-73	—	dB
Spurious-Free Dynamic Range	SFDR		—	75	—	dB

Note:
1. Absolute input pin voltage is limited by the V_{DD} supply.

Table 4.10. Voltage References

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage	V_{REFFS}		1.60	1.65	1.70	V

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Weak Pull-Up Current	I_{PU}	V_{DD} = 1.8 V V_{IN} = 0 V	—	–4	—	µA
		V_{DD} = 3.6 V V_{IN} = 0 V	–35	–20	—	µA
Input Leakage	I_{LK}	Weak pullup disabled or pin in analog mode	–1	—	1	µA

4.2 Thermal Conditions

Table 4.15. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance[1]	θ_{JA}	QFN-24 Packages	—	35	—	°C/W
		QFN-32 Packages	—	28	—	°C/W
		QFP-32 Packages	—	80	—	°C/W

Note:
1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.

4.3 Absolute Maximum Ratings

Stresses above those listed in Table 4.16 Absolute Maximum Ratings on page 19 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.16. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		–55	125	°C
Storage Temperature	T_{STG}		–65	150	°C
Voltage on V_{DD}	V_{DD}		GND–0.3	4.0	V
Voltage on I/O pins or RSTb	V_{IN}	V_{DD} > 2.2 V	GND–0.3	5.8	V
		V_{DD} <= 2.2 V	GND–0.3	V_{DD} + 3.6	V
Total Current Sunk into Supply Pin	I_{VDD}		—	400	mA
Total Current Sourced out of Ground Pin	I_{GND}		400	—	mA
Current Sourced or Sunk by Any I/O Pin or RSTb	I_{IO}		-100	100	mA
Maximum Total Current through all Port Pins	I_{IOTOT}		—	200	mA
Operating Junction Temperature	T_J		–40	105	°C
Exposure to maximum rating conditions for extended periods may affect device reliability.					

4.4 Typical Performance Curves

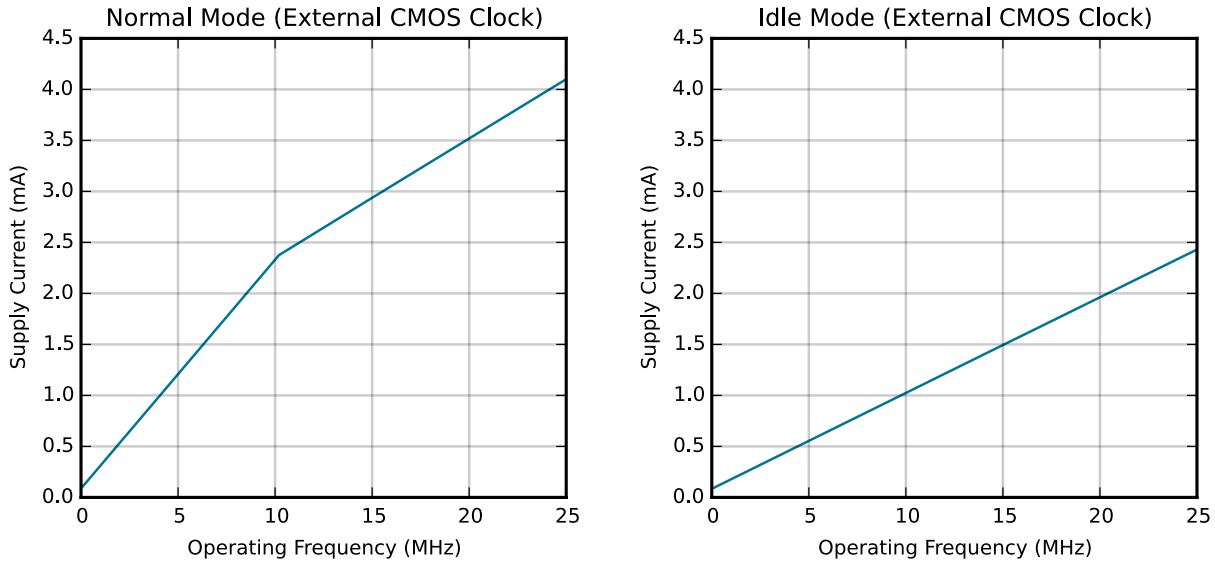

Figure 4.1. Typical Operating Supply Current (full supply voltage range)

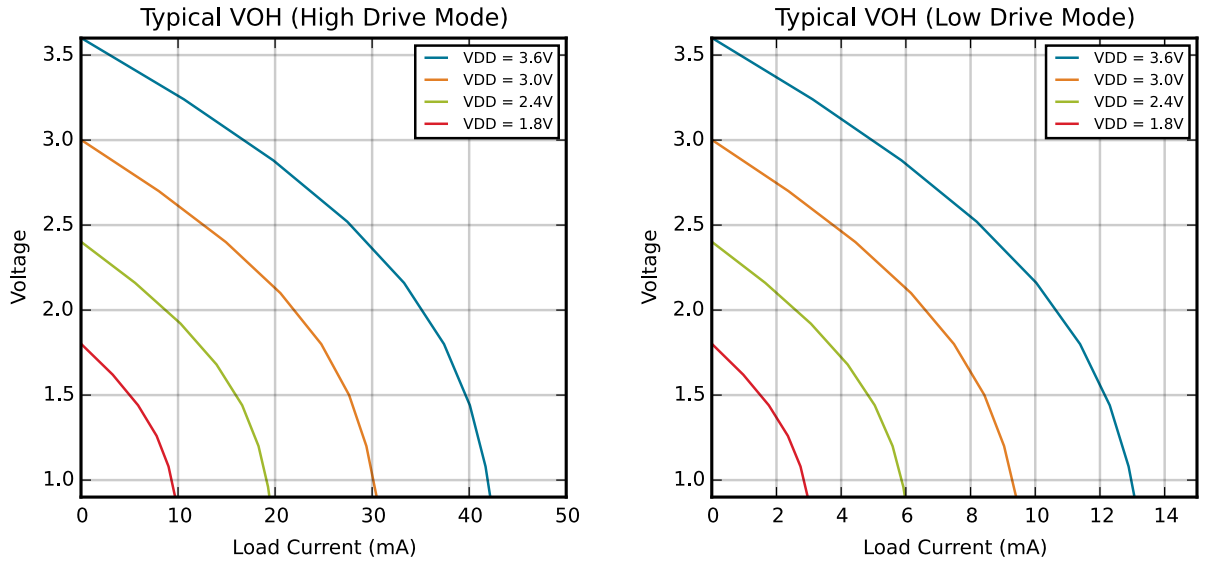

Figure 4.2. Typical V_{OH} Curves

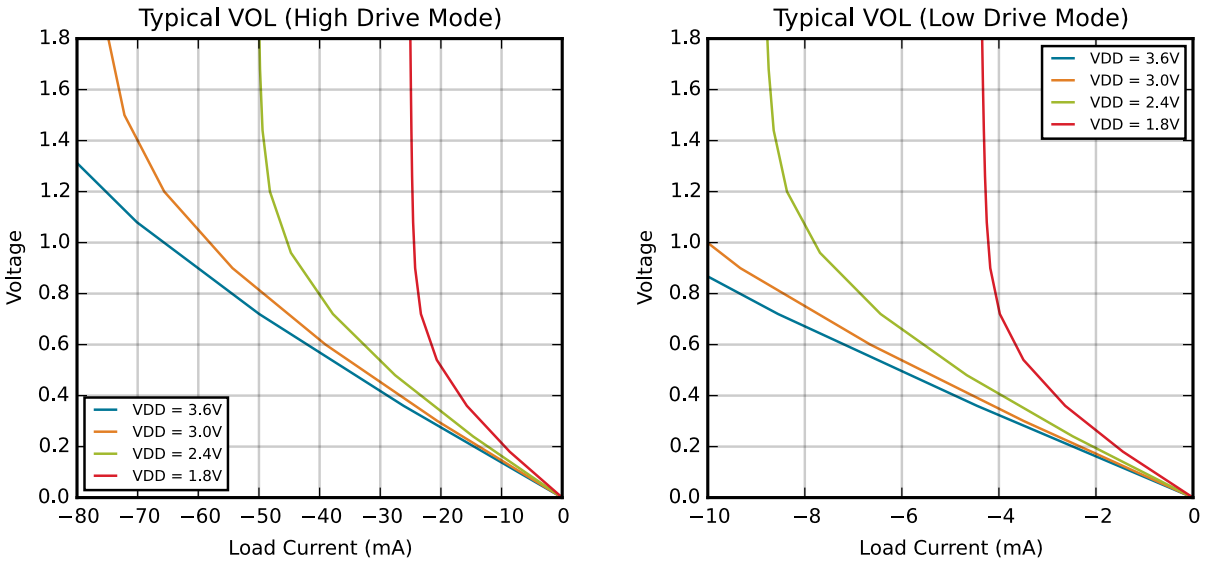

Figure 4.3. Typical V_{OL} Curves

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
19	P1.5	Multifunction I/O	Yes	P1MAT.5 EMIF_AD5	ADC0.13 CMP0N.6 CMP1N.6
20	P1.4	Multifunction I/O	Yes	P1MAT.4 EMIF_AD4	ADC0.12 CMP0P.6 CMP1P.6
21	P1.3	Multifunction I/O	Yes	P1MAT.3 SPI1_NSS EMIF_AD3	ADC0.11 CMP0N.5 CMP1N.5
22	P1.2	Multifunction I/O	Yes	P1MAT.2 SPI1_MOSI EMIF_AD2	ADC0.10 CMP0P.5 CMP1P.5
23	P1.1	Multifunction I/O	Yes	P1MAT.1 SPI1_MISO EMIF_AD1	ADC0.9 CMP0N.4 CMP1N.4
24	P1.0	Multifunction I/O	Yes	P1MAT.0 SPI1_SCK EMIF_AD0	ADC0.8 CMP0P.4 CMP1P.4
25	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 IREF0 CMP0N.3 CMP1N.3
26	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CMP0P.3 CMP1P.3
27	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5	ADC0.5 CMP0N.2 CMP1N.2
28	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4	ADC0.4 CMP0P.2 CMP1P.2
29	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3	ADC0.3 XTAL2 CMP0N.1 CMP1N.1

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
30	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2	ADC0.2 CMP0P.1 CMP1P.1 XTAL1
31	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 AGND CMP0N.0 CMP1N.0
32	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP1P.0 VREF
Center	GND	Ground			

6.2 EFM8SB2x-QFN24 Pin Definitions

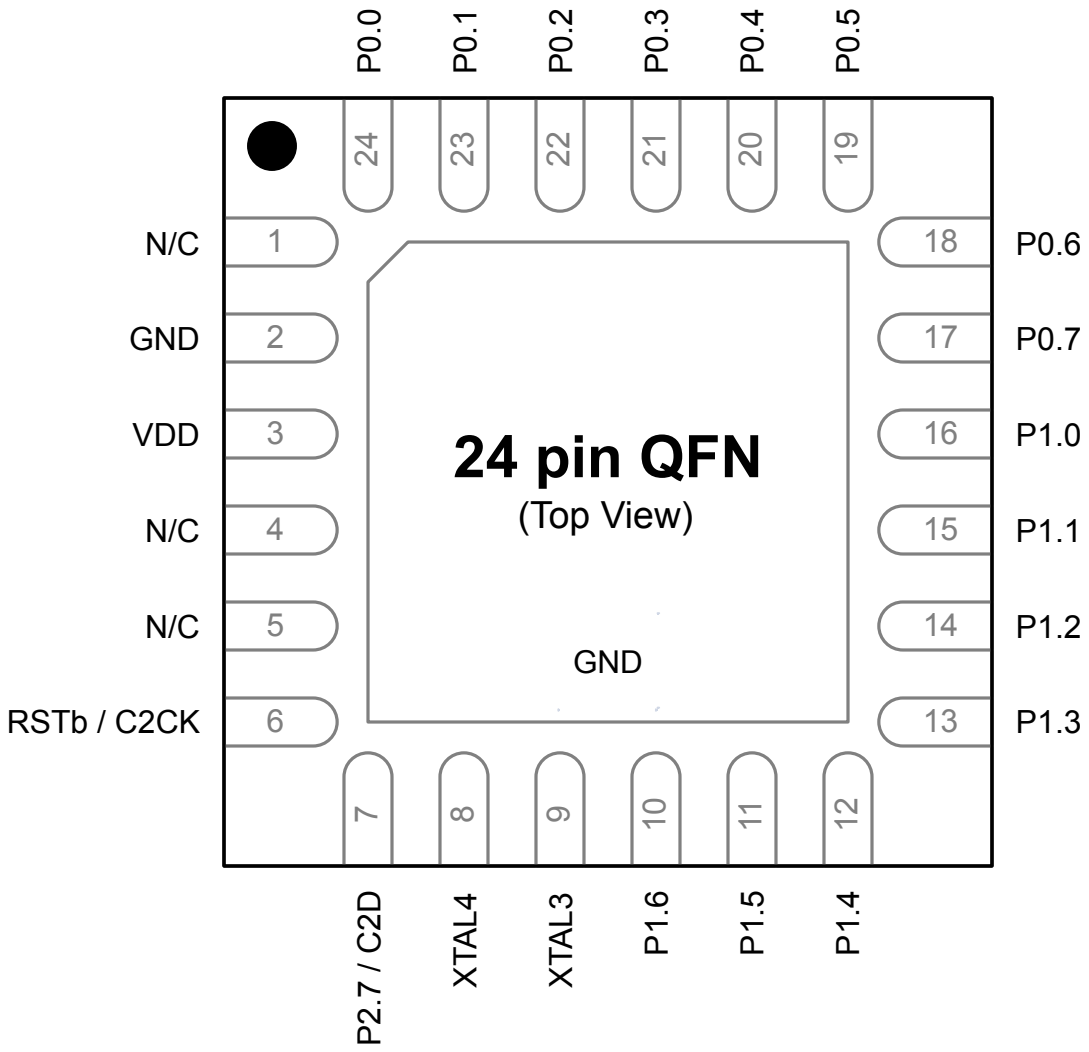

Figure 6.2. EFM8SB2x-QFN24 Pinout

Table 6.2. Pin Definitions for EFM8SB2x-QFN24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	N/C	No Connection			
2	GND	Ground			
3	VDD	Supply Power Input			
4	N/C	No Connection			
5	N/C	No Connection			

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
19	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5	ADC0.5 CMP0N.2 CMP1N.2
20	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4	ADC0.4 CMP0P.2 CMP1P.2
21	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3	ADC0.3 XTAL2 CMP0N.1 CMP1N.1
22	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2	ADC0.2 CMP0P.1 CMP1P.1 XTAL1
23	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 AGND CMP0N.0 CMP1N.0
24	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP1P.0 VREF
Center	GND	Ground			

6.3 EFM8SB2x-QFP32 Pin Definitions

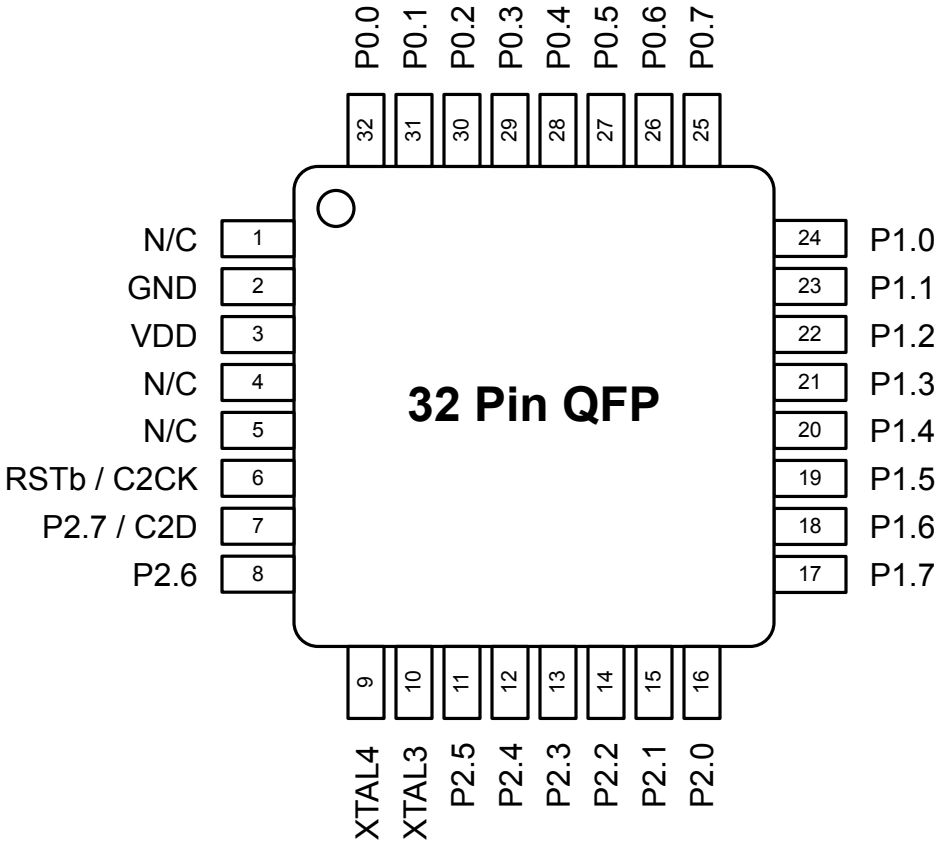

Figure 6.3. EFM8SB2x-QFP32 Pinout

Table 6.3. Pin Definitions for EFM8SB2x-QFP32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	N/C	No Connection			
2	GND	Ground			
3	VDD	Supply Power Input			
4	N/C	No Connection			
5	N/C	No Connection			
6	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
7	P2.7 / C2D	Multifunction I/O / C2 Debug Data			

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
8	P2.6	Multifunction I/O	Yes	EMIF_WRb	ADC0.22 CMP0P.11 CMP1P.11
9	XTAL4	RTC Crystal			XTAL4
10	XTAL3	RTC Crystal			XTAL3
11	P2.5	Multifunction I/O	Yes	EMIF_RDb	ADC0.21 CMP0N.10 CMP1N.10
12	P2.4	Multifunction I/O	Yes	EMIF_ALE	ADC0.20 CMP0P.10 CMP1P.10
13	P2.3	Multifunction I/O	Yes	EMIF_A11	ADC0.19 CMP0N.9 CMP1N.9
14	P2.2	Multifunction I/O	Yes	EMIF_A10	ADC0.18 CMP0P.9 CMP1P.9
15	P2.1	Multifunction I/O	Yes	EMIF_A9	ADC0.17 CMP0N.8 CMP1N.8
16	P2.0	Multifunction I/O	Yes	EMIF_A8	ADC0.16 CMP0P.8 CMP1P.8
17	P1.7	Multifunction I/O	Yes	P1MAT.7 EMIF_AD7	ADC0.15 CMP0N.7 CMP1N.7
18	P1.6	Multifunction I/O	Yes	P1MAT.6 EMIF_AD6	ADC0.14 CMP0P.7 CMP1P.7
19	P1.5	Multifunction I/O	Yes	P1MAT.5 EMIF_AD5	ADC0.13 CMP0N.6 CMP1N.6
20	P1.4	Multifunction I/O	Yes	P1MAT.4 EMIF_AD4	ADC0.12 CMP0P.6 CMP1P.6

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
31	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 AGND CMP0N.0 CMP1N.0
32	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP1P.0 VREF

Dimension	Min	Typ	Max
bbb	—	—	0.10
ddd	—	—	0.05
eee	—	—	0.08

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-220, variation VHHD except for custom features D2, E2, and L which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

Dimension	Min	Max

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
5. The stencil thickness should be 0.125 mm (5 mils).
6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
7. A 2 x 2 array of 1.10 mm x 1.10 mm openings on 1.30 mm pitch should be used for the center ground pad.
8. A No-Clean, Type-3 solder paste is recommended.
9. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

8.3 QFN24 Package Marking

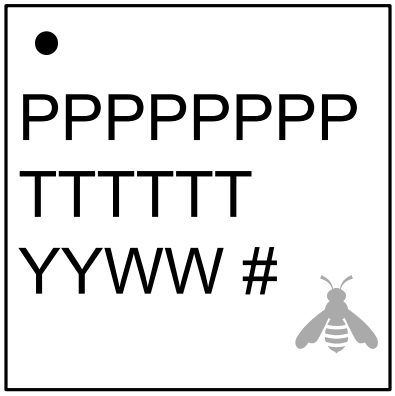

Figure 8.3. QFN24 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

9. QFP32 Package Specifications

9.1 QFP32 Package Dimensions

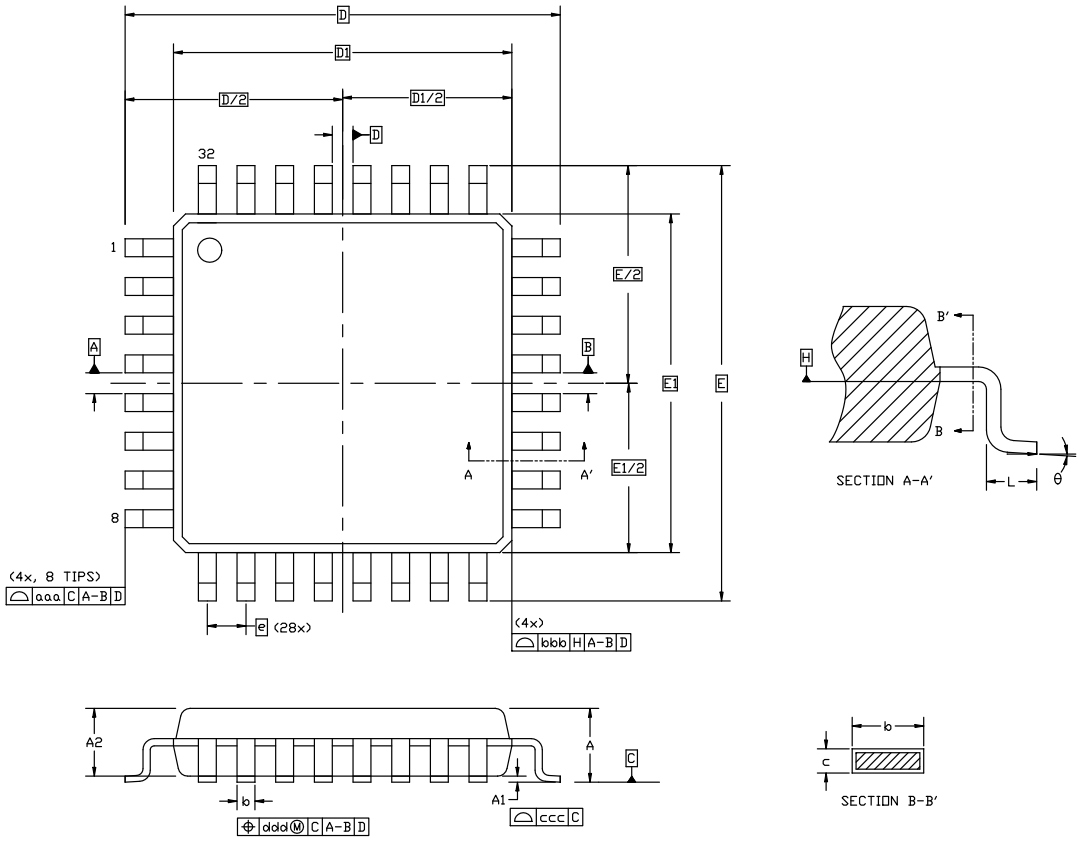

Figure 9.1. QFP32 Package Drawing

Table 9.1. QFP32 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.60
A1	0.05	—	0.15
A2	1.35	1.40	1.45
b	0.30	0.37	0.45
D		9.00 BSC	
D1		7.00 BSC	
e		0.80 BSC	
E		9.00 BSC	
E1		7.00 BSC	
L	0.45	0.60	0.75
aaa		0.20	

9.3 QFP32 Package Marking

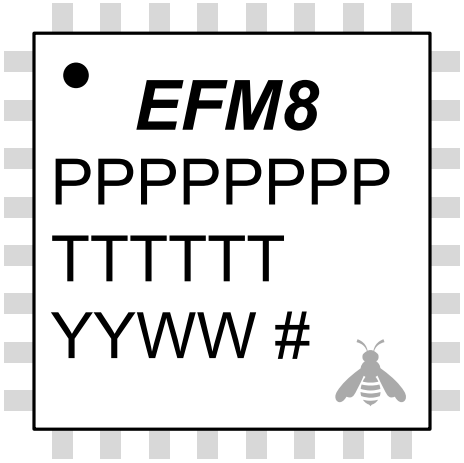

Figure 9.3. QFP32 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).